

GISAS for soft matter

P. Müller-Buschbaum

Technische Universität München, Lehrstuhl für Funktionelle Materialien,
Physik-Department, James-Franck-Str. 1, 85748 Garching, Germany

Technische Universität München, Heinz Maier-Leibnitz Zentrum (MLZ),
Forschungs-Neutronenquelle Heinz Maier-Leibnitz (FRM II),
Lichtenbergstraße 1, 85748 Garching, Germany

Outline

1. General introduction
2. Selected X-Ray Examples
3. Selected Neutron Examples

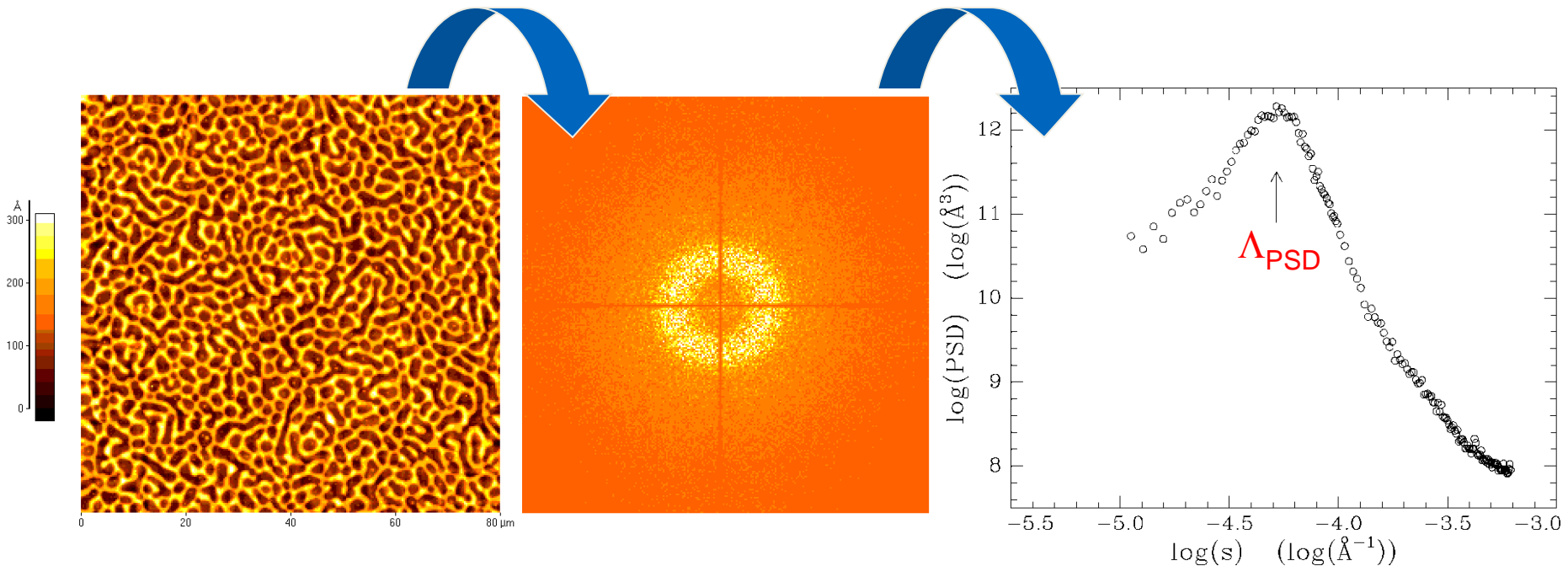




German Black Forest Cherry Cake
looking for a more non-destructive way ...

Statistical analysis of AFM data

isotropic structure \rightarrow circular ring \rightarrow well described by one in-plane length

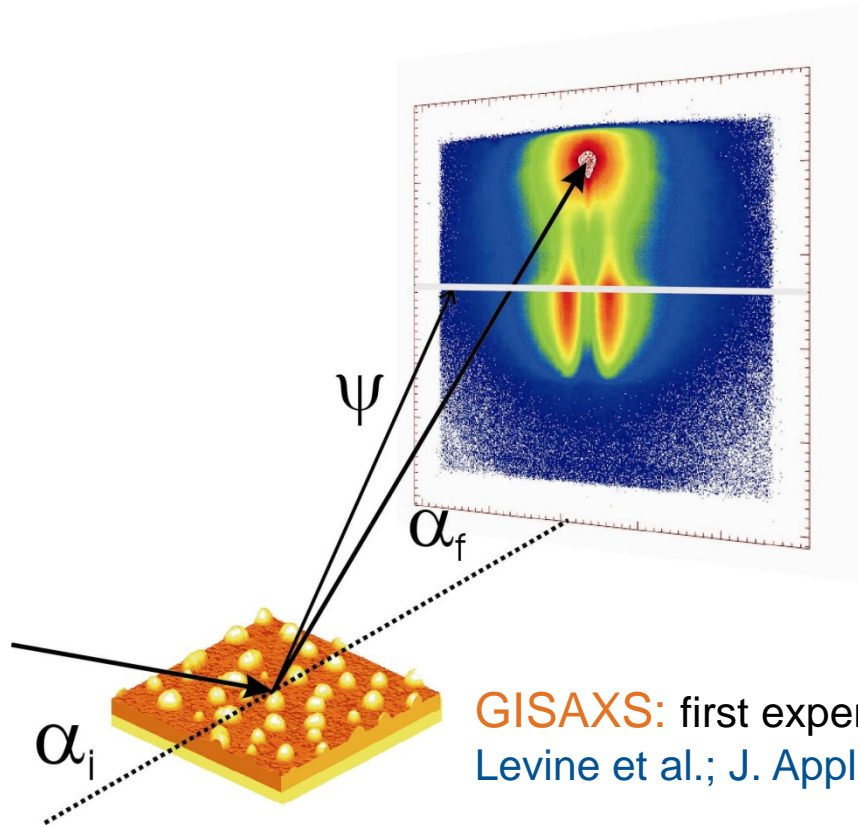


AFM data accessible with scan ranges up to $\approx 100 \mu\text{m}$

\rightarrow determination of most prominent in-plane length Λ_{PSD}

\rightarrow only sample surface probed !

GISAS (grazing incidence small angle scattering)



- fixed incidence angle $\alpha_i \ll 1^\circ$
- two high quality entrance cross-slits
- mostly evacuated pathway
- two dimensional detector array
- controlling sample position and orientation with respect to the beam

**sample-detector distance
determines resolution**
→ **sub-nm up to several μm**

GISAXS: first experiment:
Levine et al.; J. Appl. Cryst. **22**, 528 (1989)

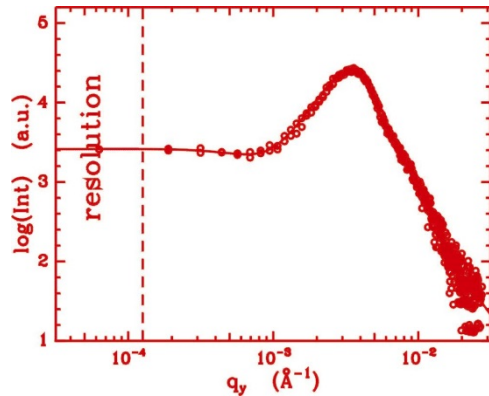
GISANS:
Müller-Buschbaum et al.; Colloid.Polym.Sci. **277**, 1193 (1999)

Review: Müller-Buschbaum; Polymer Journal **45**, 34 (2013)



Line cuts

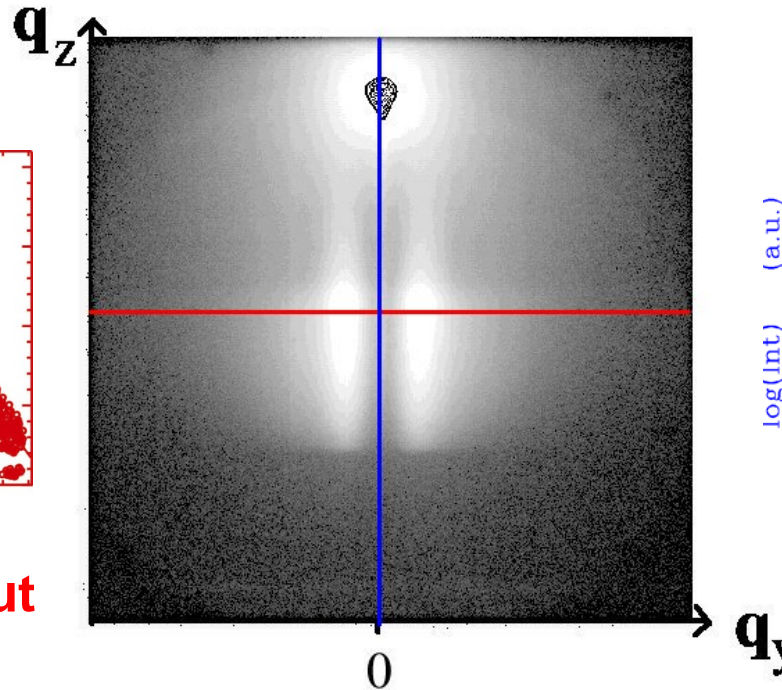
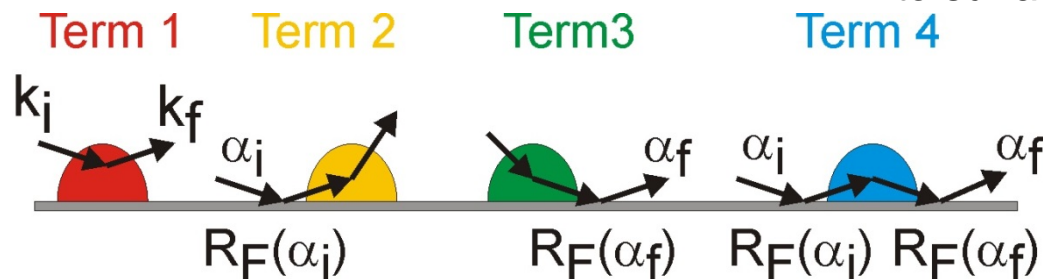
cut at constant q_z



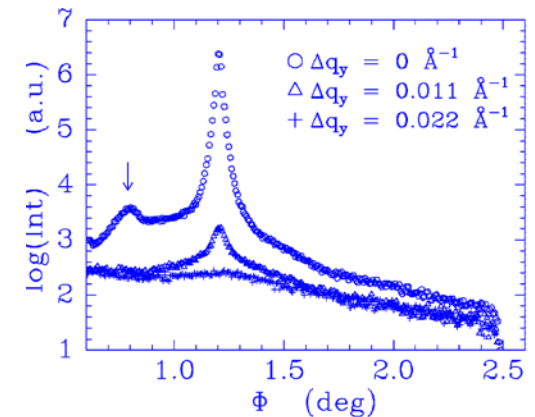
horizontal line cut

→ q_y -dependence:
in-plane structures

Distorted-wave Born
approximation:



cut at constant q_y



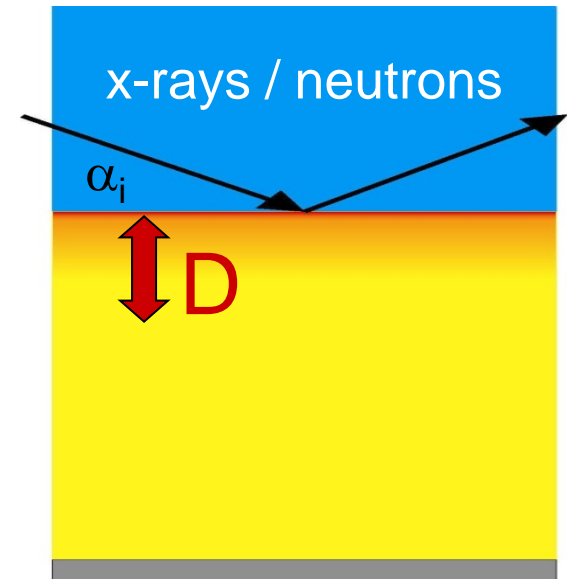
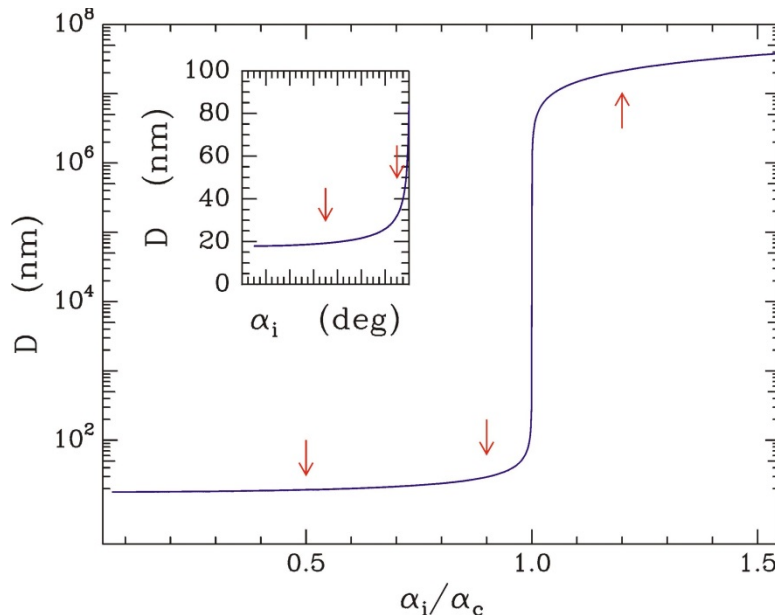
vertical line cut

→ mainly q_z -dependence:
correlation perpendicular
to surface

Surface sensitivity

scattering depth of x-rays or neutrons

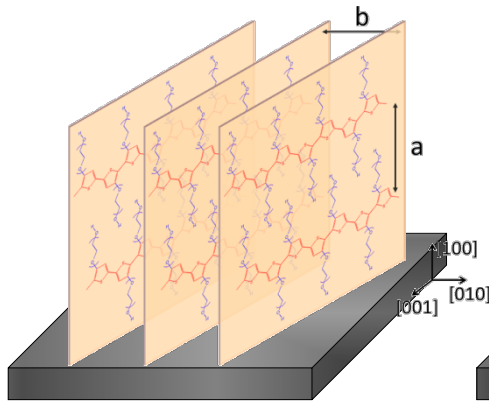
$$D = \frac{\lambda}{\sqrt{2\pi}(l_i + l_f)} \quad l_{i,f} = \left[\sin^2 \alpha_c - \sin^2 \alpha_{i,f} + \sqrt{(\sin^2 \alpha_{i,f} - \sin^2 \alpha_c)^2 + \left(\frac{\mu\lambda}{2\pi}\right)^2} \right]^{1/2}$$



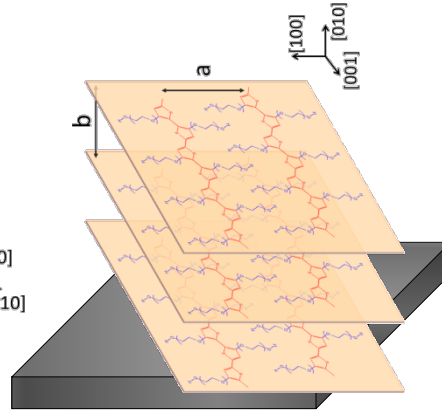
→ vary incident angle $\alpha_i < \alpha_c$ to probe surface near region only or to penetrated large sample volume

GIWAXS (grazing incidence wide angle X-ray scattering)

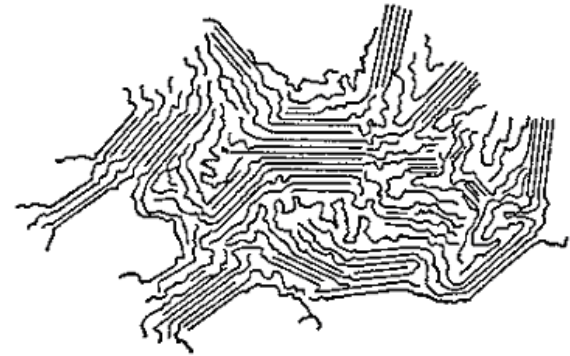
molecular order with respect to substrate



edge-on

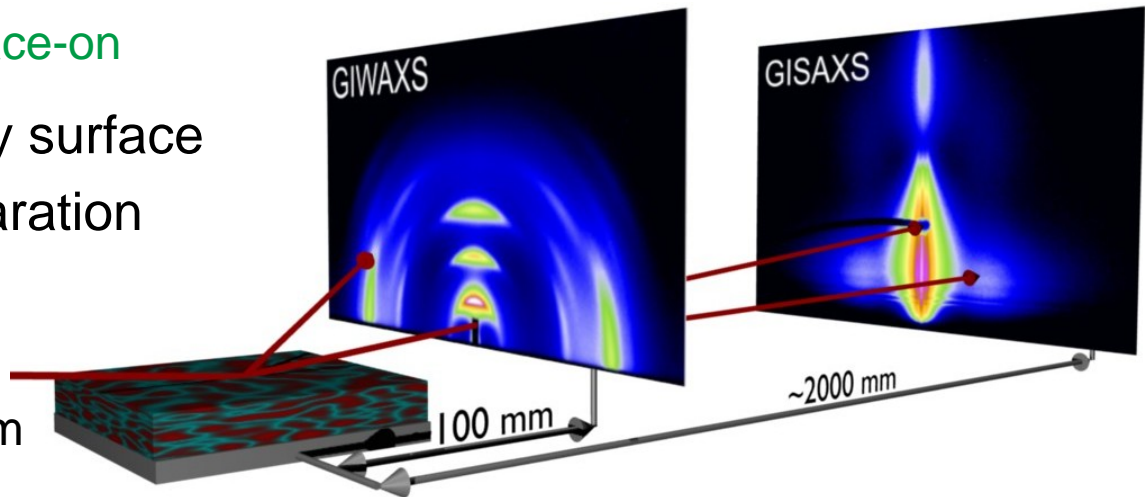


face-on

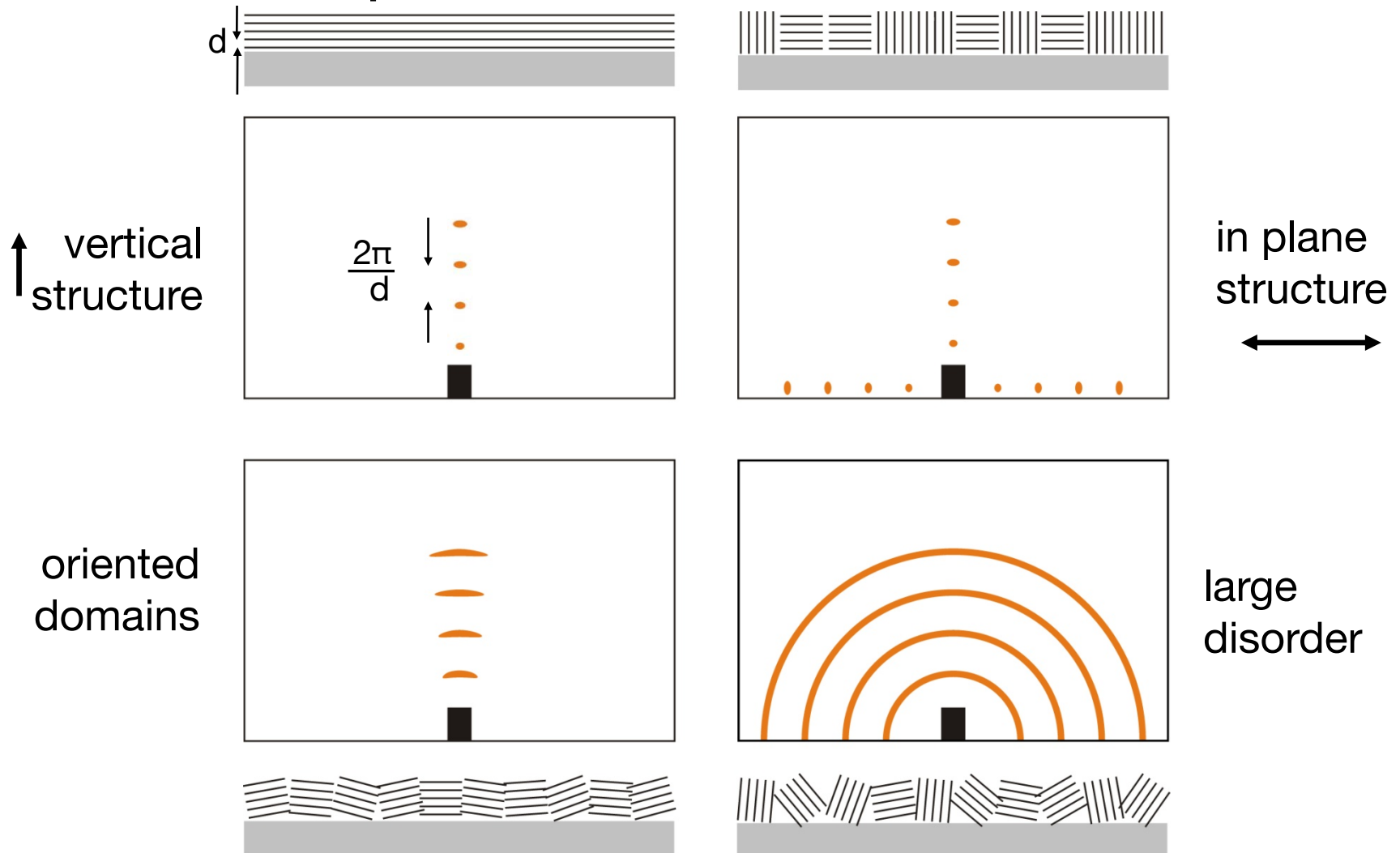


- inner structures, not only surface
- no special sample preparation

accessible length scales from
~0.1 nm to ~ 3.2 nm



GIWAXS 2D pattern



Outline

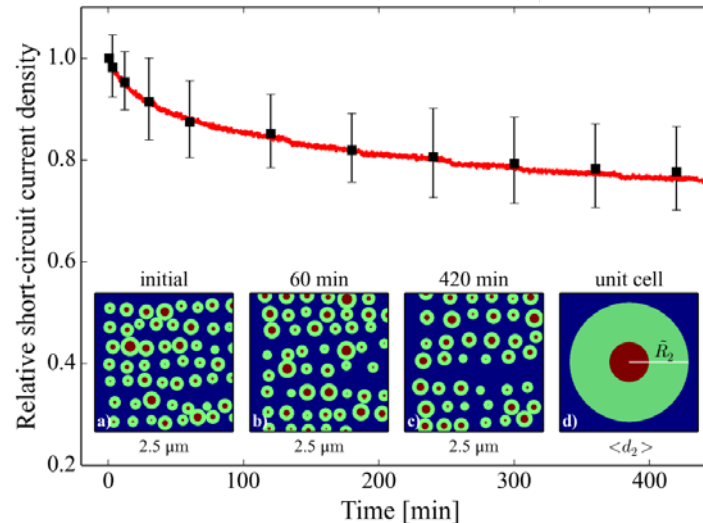
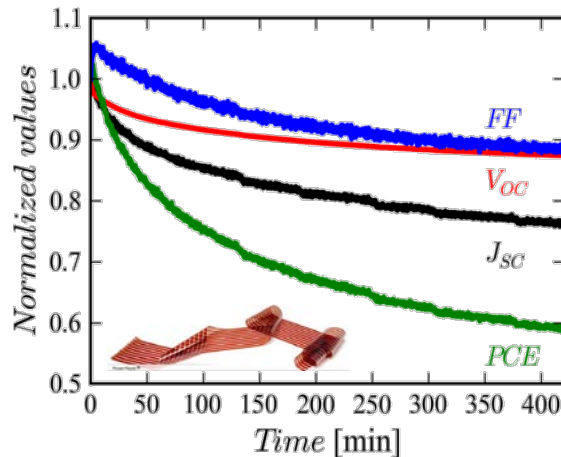
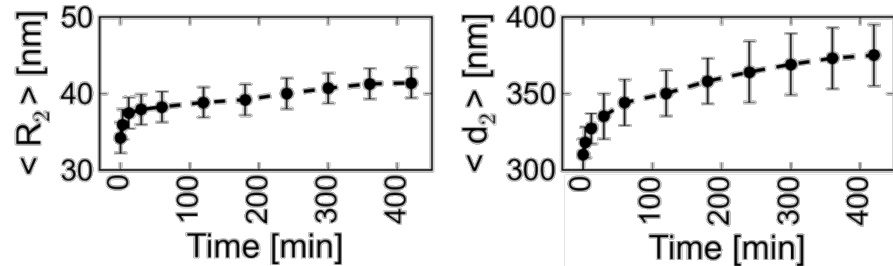
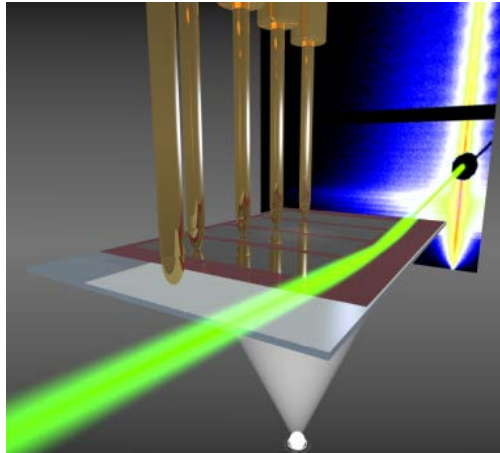
1. General introduction
2. Selected X-Ray Examples
3. Selected Neutron Examples





Structural degradation during operation

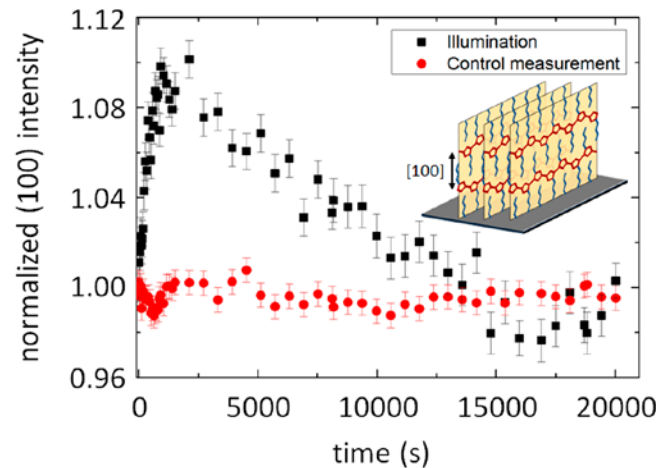
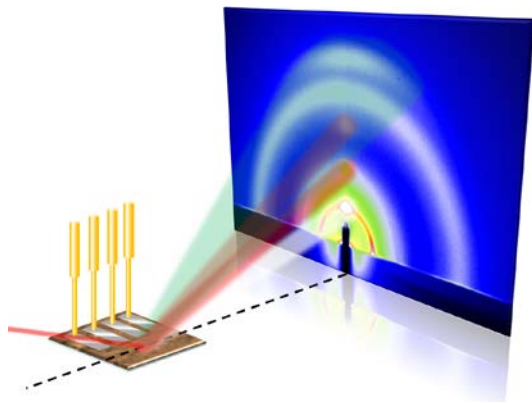
In-operando study of P3HT:PCBM BHJ solar cell in vacuum



morphological degradation as consequence of demixing reduces short-circuit current J_{sc}

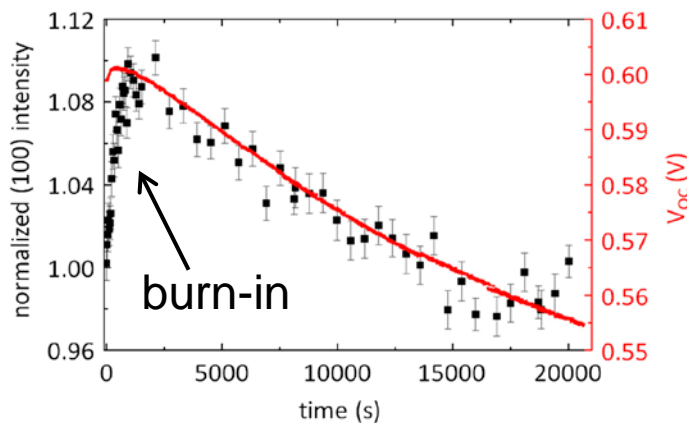
In-operando study of changes in crystalline parts

P3HT:PCBM BHJ solar cell: GIWAXS + IV tracking in air



illumination:
increase of FWHM and
change in intensities

control (dark):
no change of crystalline
P3HT parts

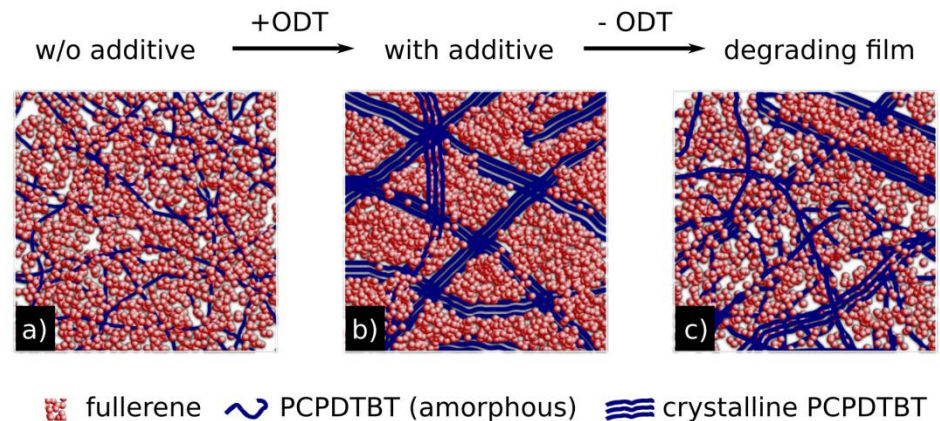
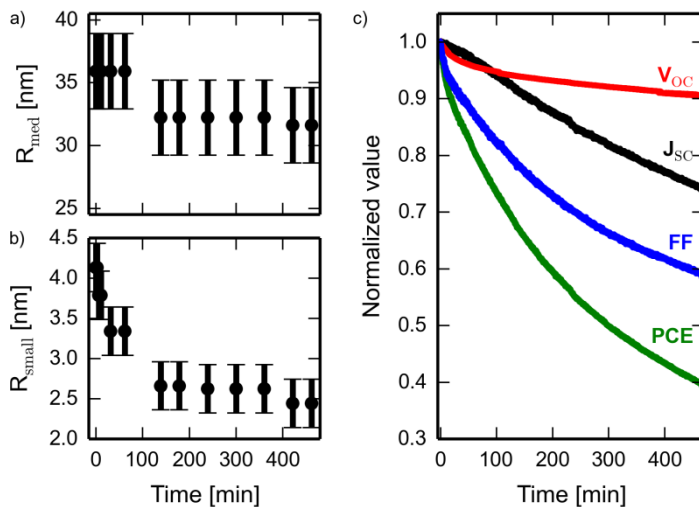


longtime exposure to light:
degradation mechanisms like oxidation,
photobleaching reduce crystallinity

link between crystalline state and photovoltage

Morphological degradation in low bandgap polymer solar cells

In-operando study of PCPDTBT:PC₇₁BM + 3 v% 1,8-octanedithiol (ODT)

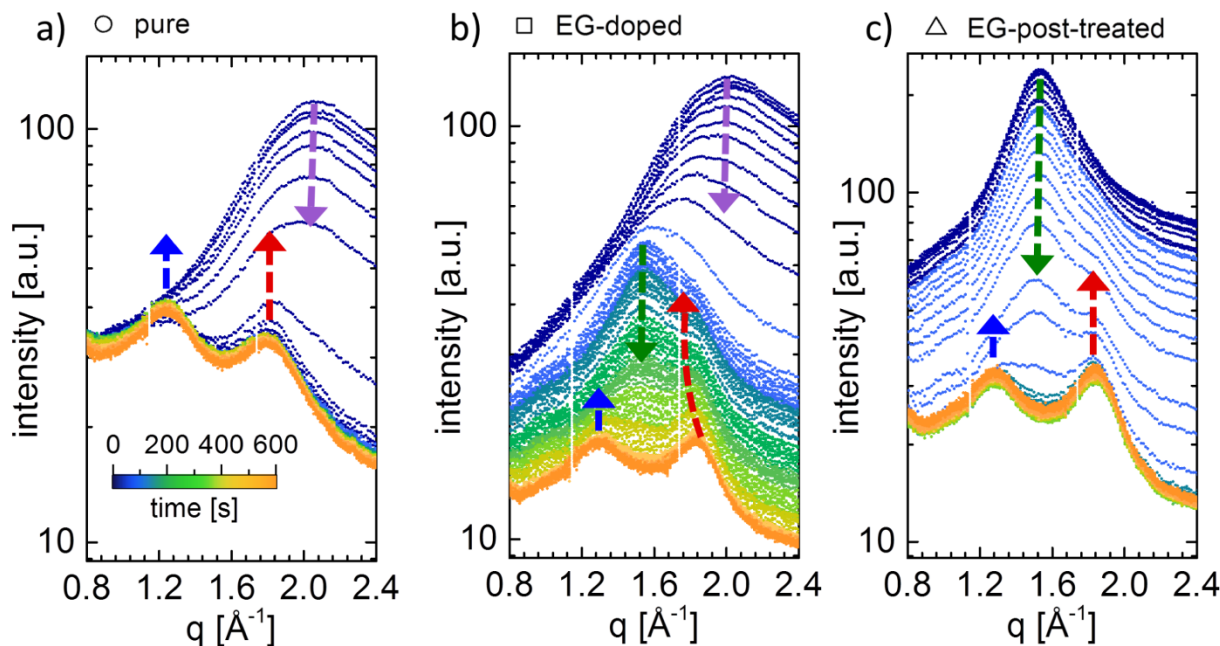


shrinking domains lose their connection to interpenetrating network
→ charge carriers get trapped in isolated domains
→ amplification of recombination lowers fill factor

one none-equilibrium state changes into another without ODT

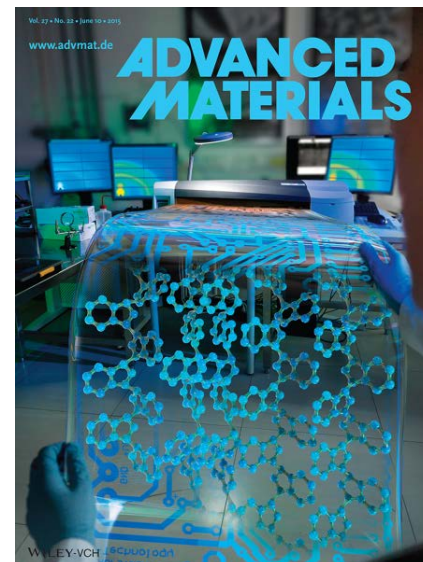
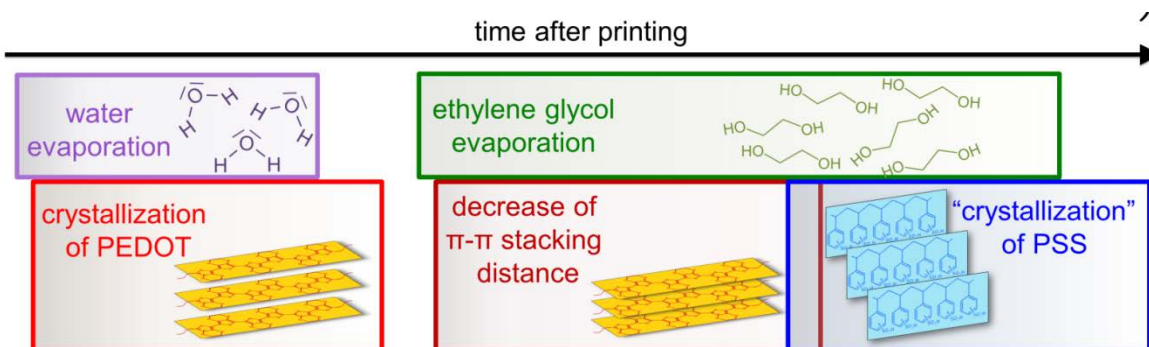


Printing of PEDOT:PSS electrodes



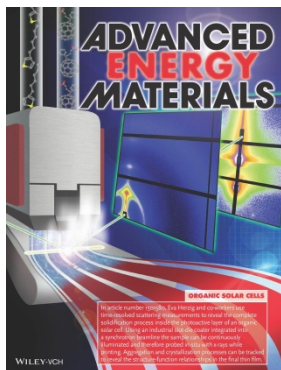
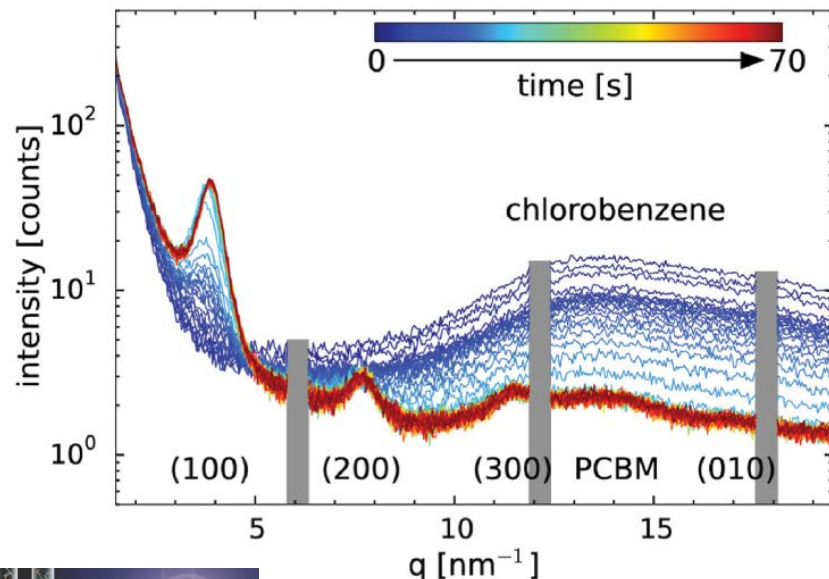
information on:

- solvent evaporation
- polymer crystallization
- film formation times & processes

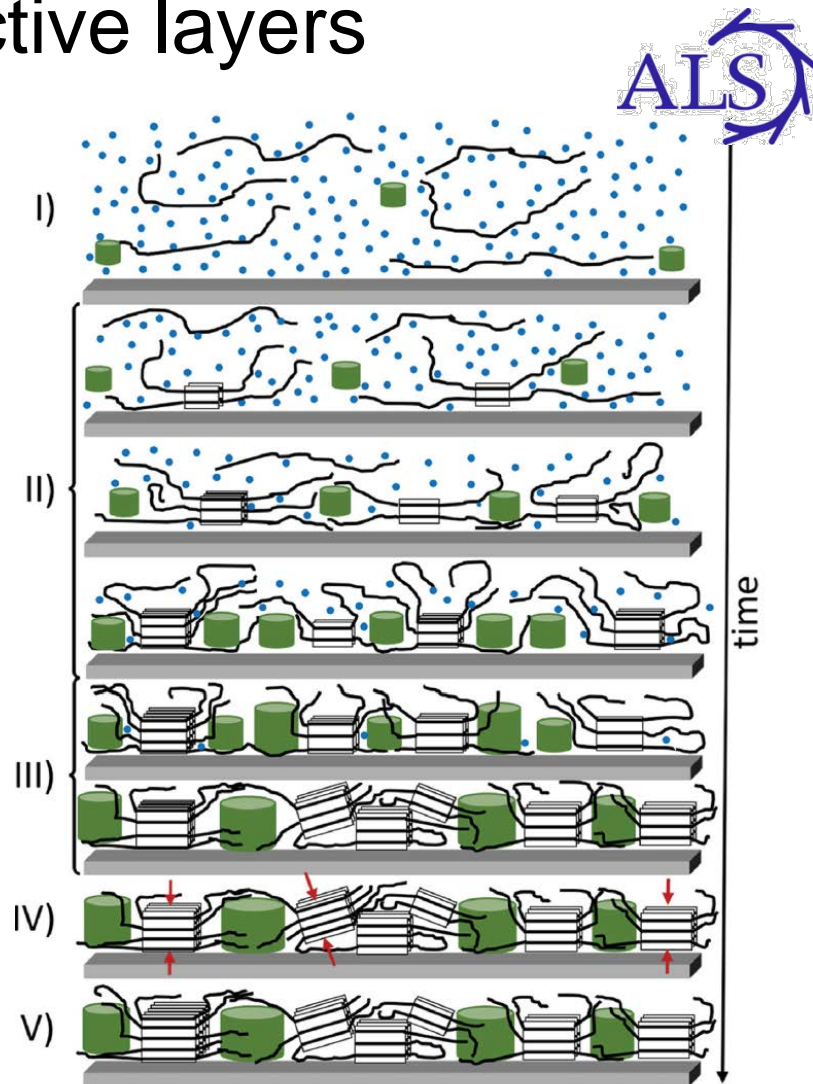


Printing of P3HT:PCBM active layers

from chlorobenzene

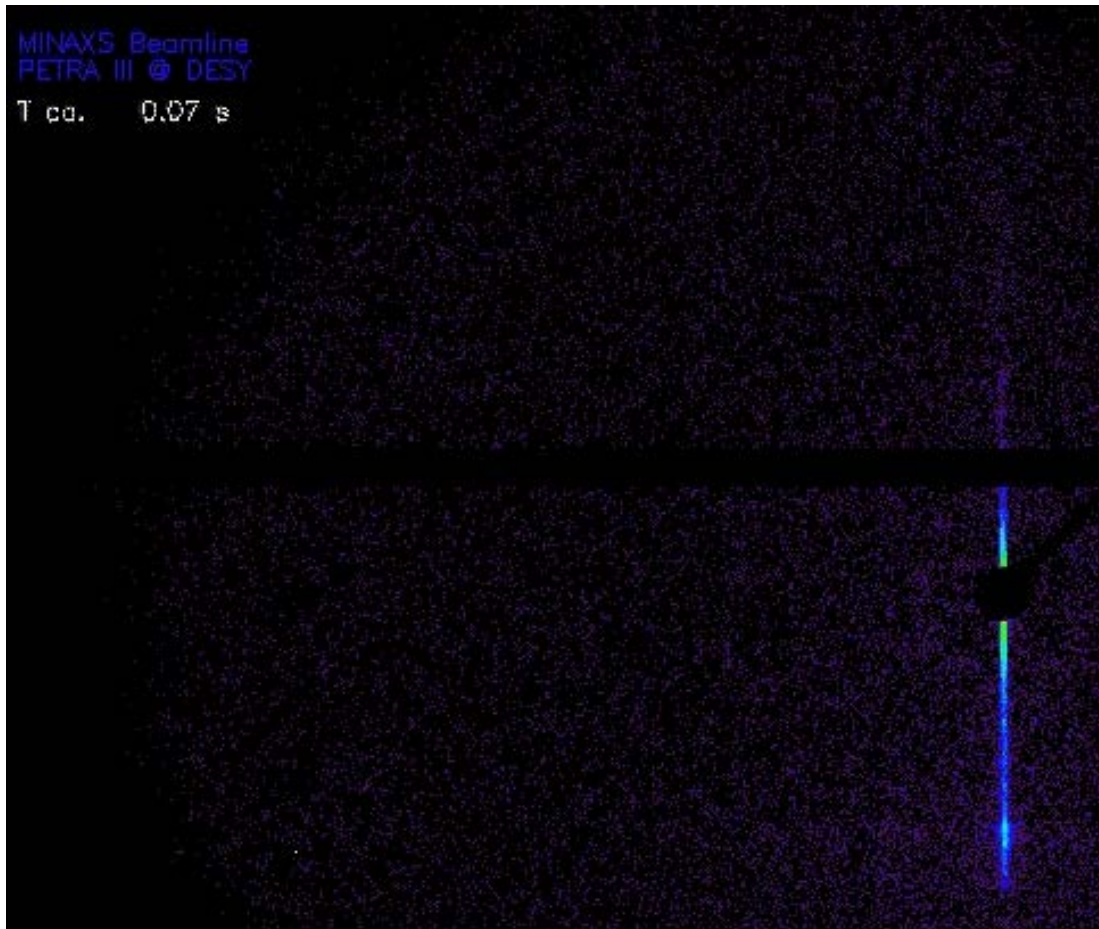


initial slow formation of P3HT crystallites in well-aligned edge-on orientation followed by a rapid crystal growth

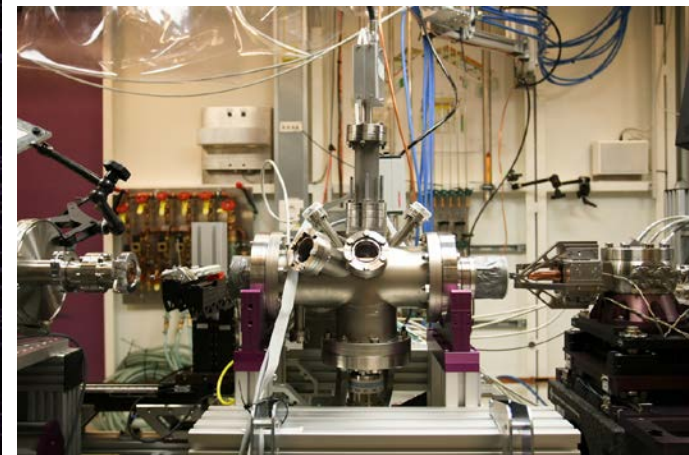


Metal top contact deposition

In-situ GISAXS during sputter deposition of gold



sputter rate = 12 nm/min



$\alpha_i = 0.41^\circ$

counting time 10 ms

exposure period 15 ms

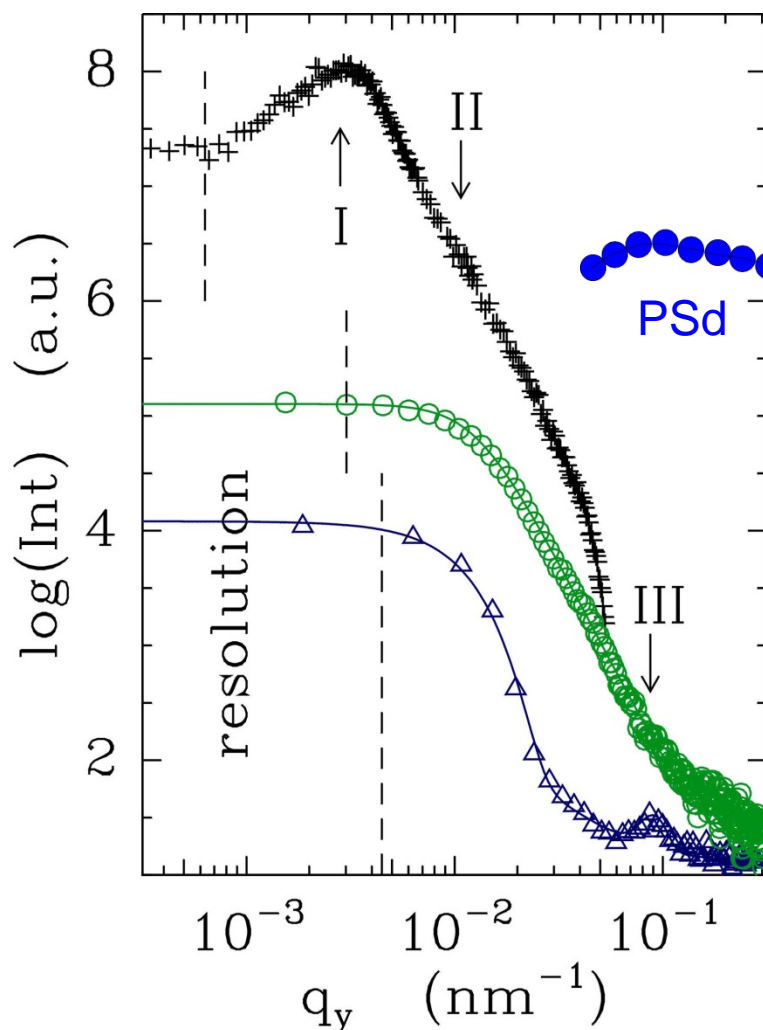
10000 frames

Outline

1. General introduction
2. Selected X-Ray Examples
3. Selected Neutron Examples

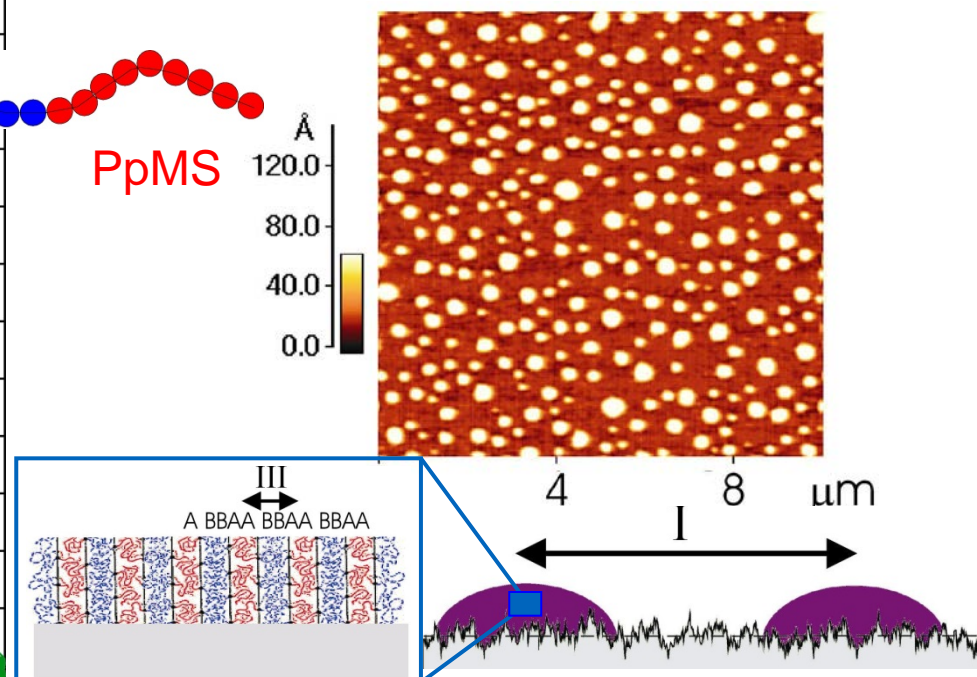


Internal nano-structure



P(Sd-b-pMS) on Si/SiO_x $h < 1/3 R_g$

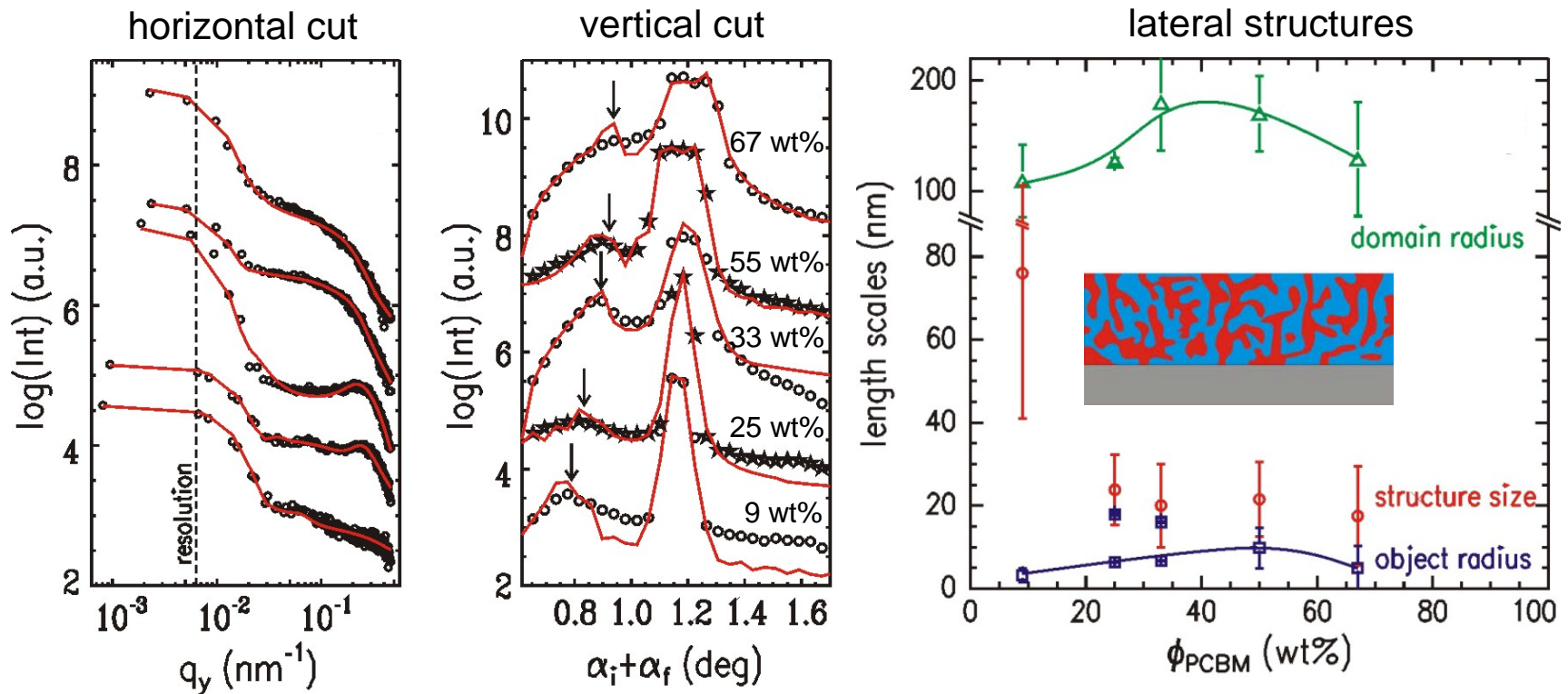
toluene vapor treatment 12h



large drops (I) only resolved by **AFM**
small structure (III) only visible with
GISANS not with **GISAXS**

Active layer of organic solar cells

P3HT:PCBM on Si/SiO_x



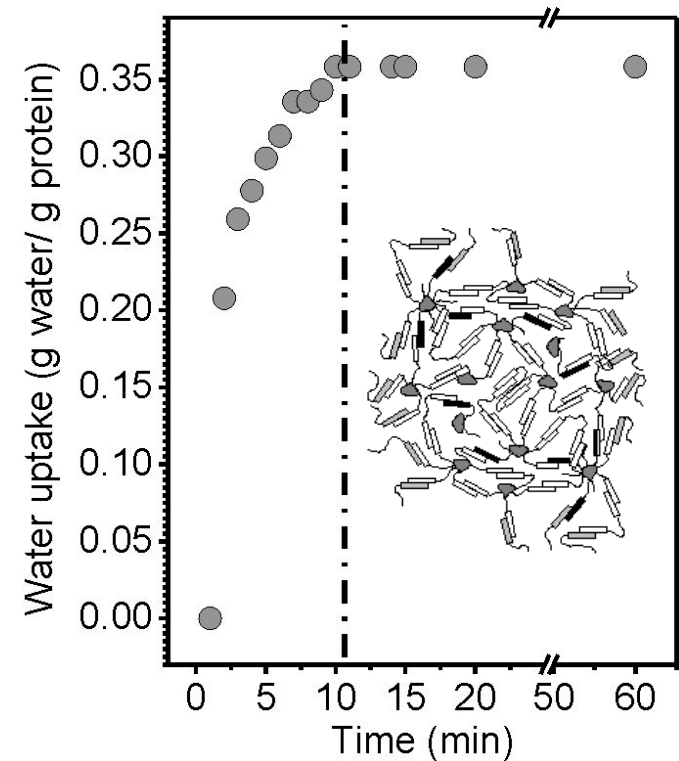
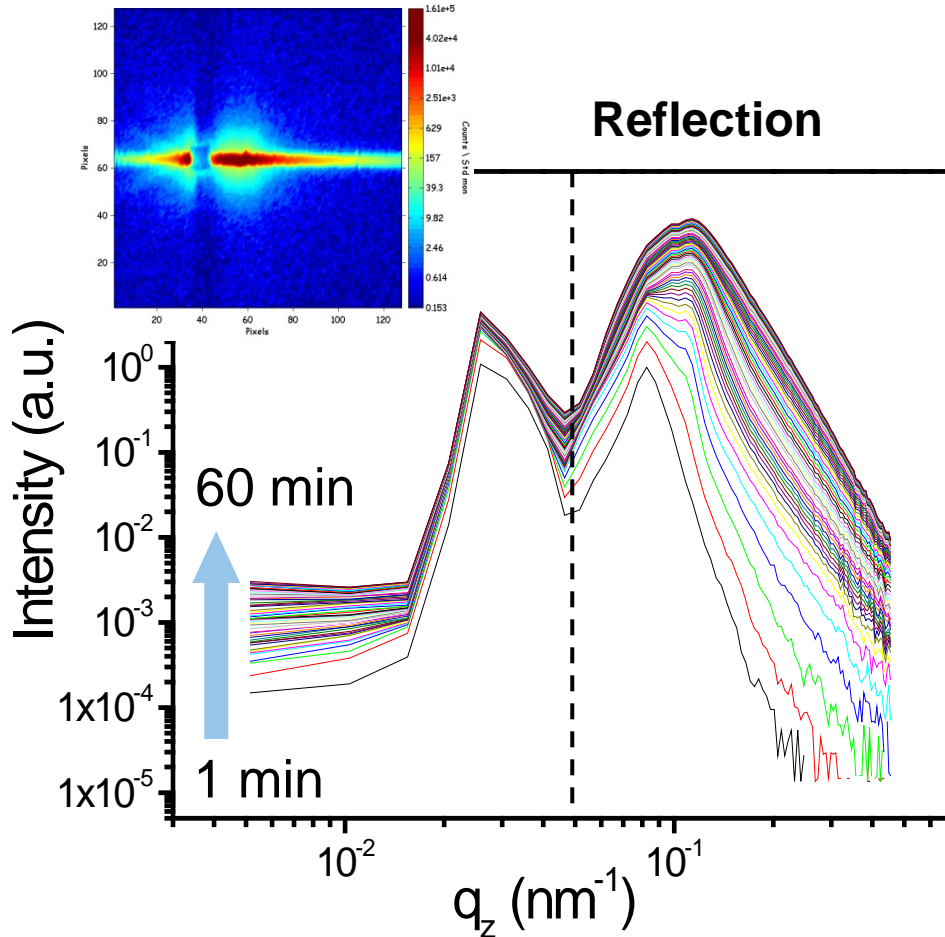
at most efficient blend ratio → structure size ~ exciton diffusion length
→ largest PCBM objects – charge transport

Ruderer, PMB et al.; J. Phys. Chem. Lett. **3**, 683 (2012)

Time resolved GISANS

swelling of dry casein film in D₂O

$\Delta t = 60$ s

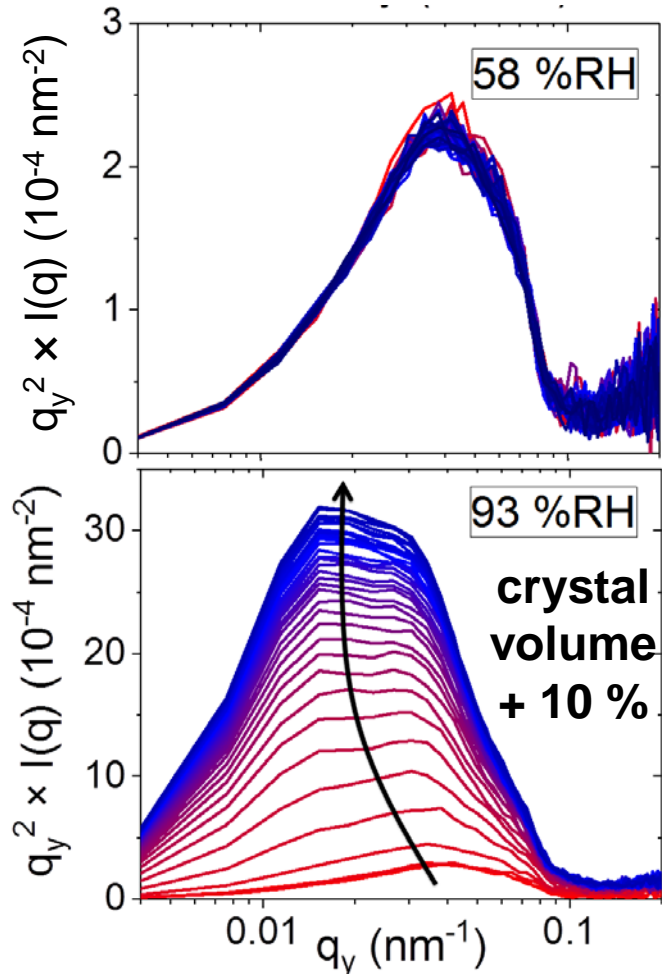


Ingression of moisture into hybrid perovskite thin films

in-situ GISANS with $\Delta t = 600$ s

- ingress of moisture at low %RH
→ level of monohydrate
→ no morphological changes
→ most water adsorbed
- sponge-like behavior at high %RH
→ strong morphological changes of crystal domains for ≥ 73 %RH
→ formation of di-hydrates

recovery of perovskite possible for certain conditions



Summary

GISAXS/GISANS open new possibilities of advanced sample characterization

GISAXS/GISANS : reciprocal space analysis technique

- *non-destructive structural probe*
- sensitive to structures between nm to μm
- does not require a special sample preparation
- *yields excellent sampling statistics*

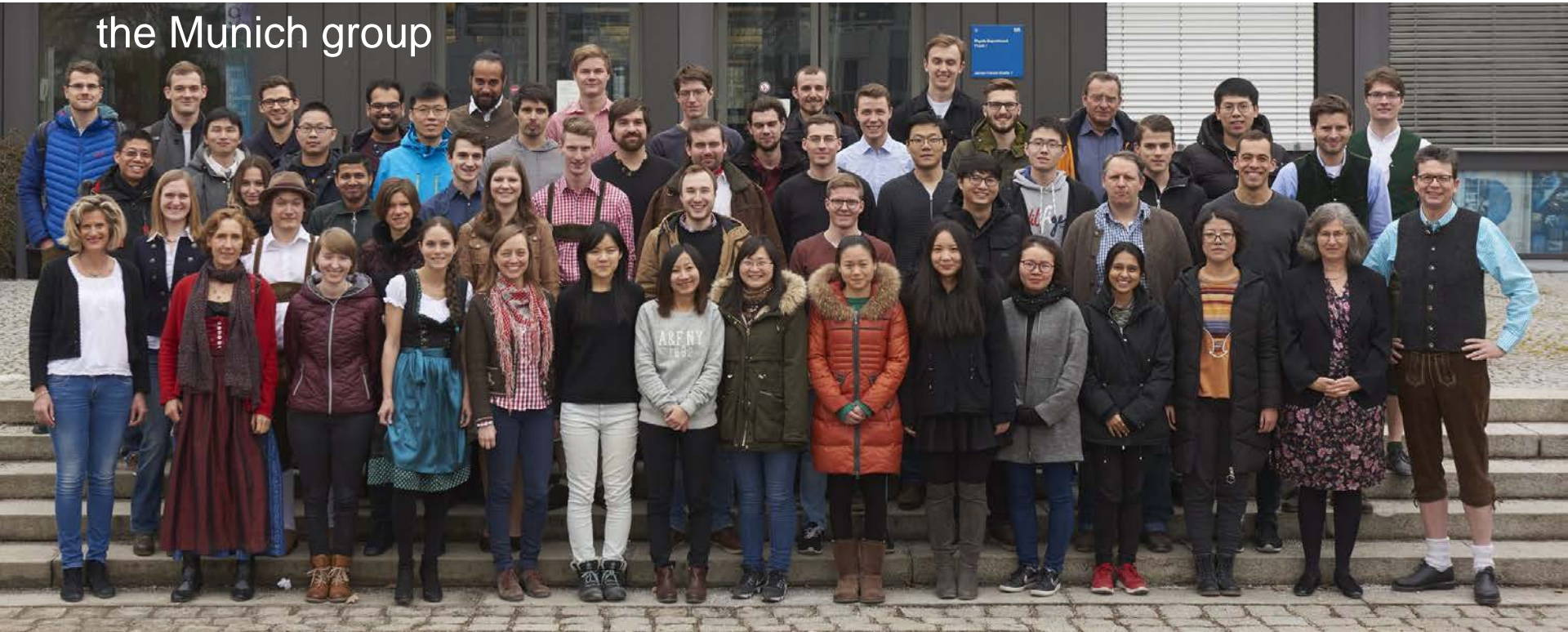
(averages over macroscopic regions to provide information on nanometer scale)



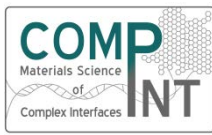
- **buried structures:** object geometry, size distributions and spatial correlations

Acknowledgments

the Munich group



Federal Ministry
of Education
and Research



Elitenetzwerk
Bayern



EuroTech Universities

SOLAR TECHNOLOGIES
GO HYBRID

TUM.solar
MSE



MaMaSELF
nim
nanosystems initiative munich



DFG IRTG 2022 NSERC

